


<b>Search Notes</b> 	<b>Application/Control No.</b> 10639925	<b>Applicant(s)/Patent Under Reexamination</b> PREIKSZAS ET AL.
	<b>Examiner</b> TOAN M LE	<b>Art Unit</b> 2863

SEARCHED			
Class	Subclass	Date	Examiner
702	107, 85	2/11/08	TL
250	396R, 201.3, 311	2/11/08	TL
359	383, 17	2/11/08	TL
382	255	2/11/08	TL

SEARCH NOTES		
Search Notes	Date	Examiner
702/107, 85; 250/396R, 201.3, 311; 359/383, 17; 382/255 (Electron Microscope Tune Index Interpolation)	2/11/08	TL
Electron Microscope Tune Index Interpolate	2/11/08	TL
East- See Search History Printout	2/13/08	TL
IEEE Xplore, ScienceDirect, Web Search	2/13/08	TL

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner